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Erratum

Erratum to "Structural, optical and electrical properties of $CuIn_5S_8$ thin films grown by thermal evaporation method" [J. Alloys Compd. 509 (2011) 6004–6008]

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ARTICLE INFO

The publisher regrets that all the figures and their captions were incorrectly published in the original version of the article. The corrected version of the Figs. 1–6 and their captions are as follows:

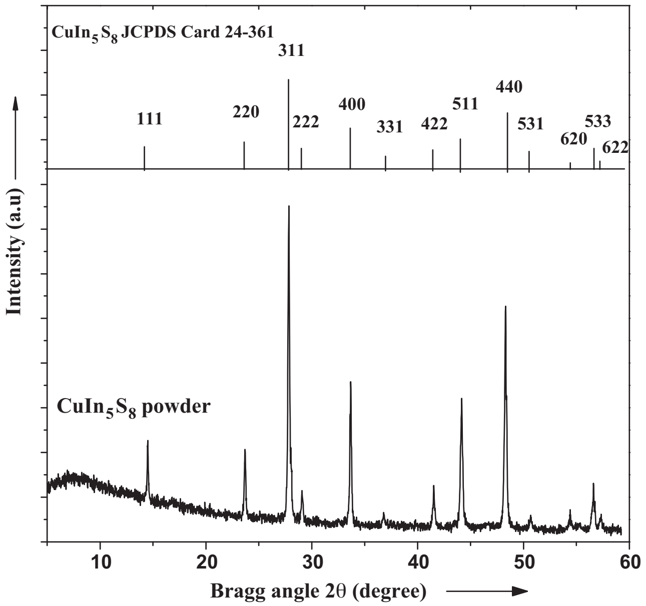

Fig. 1. XRD pattern of $CuIn_5S_8$ powder.

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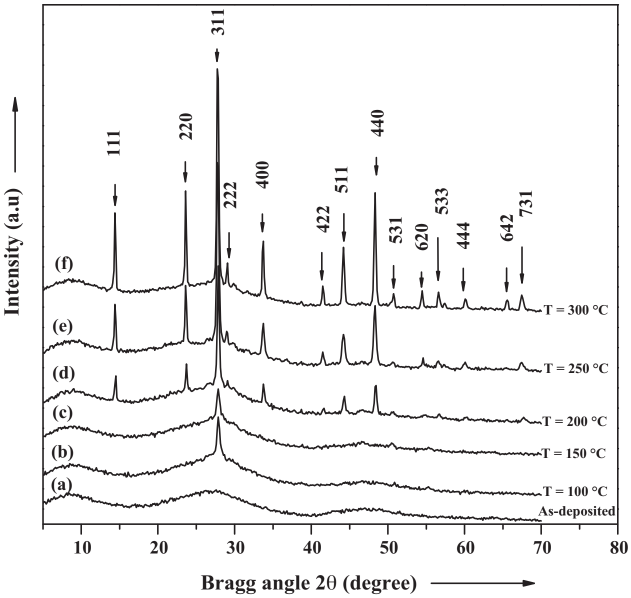

Fig. 2. XRD pattern of as-deposited and thermally annealed $CuIn_5S_8$ thin films.

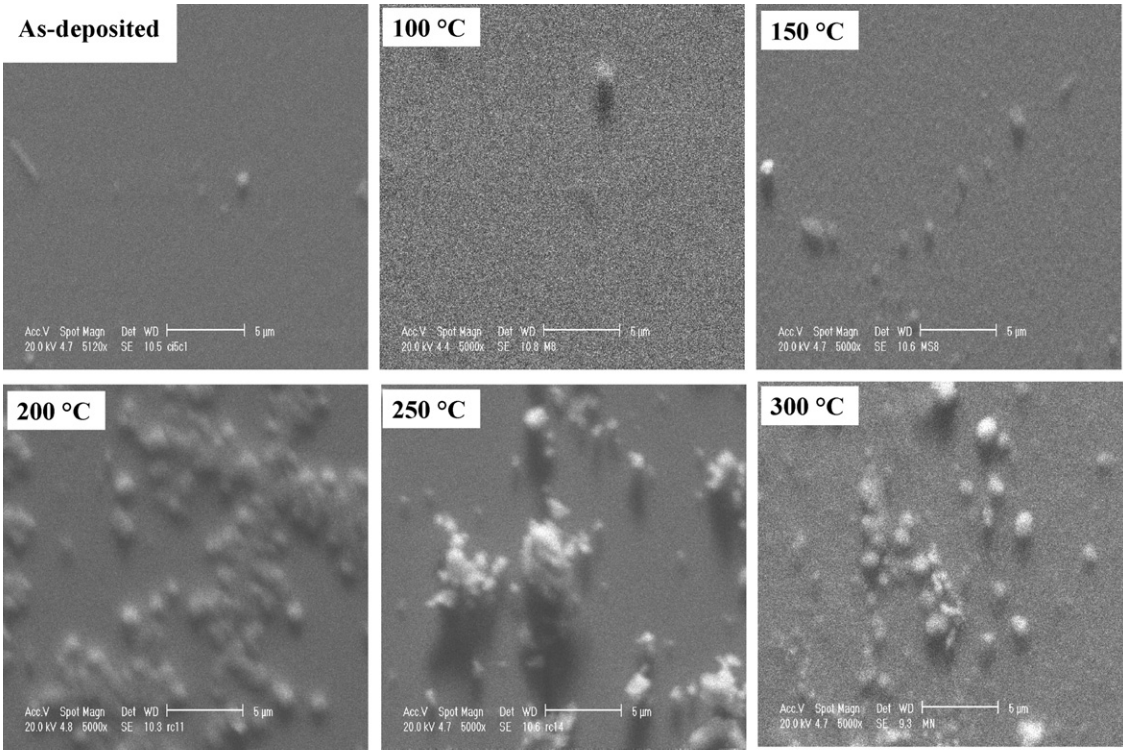

Fig. 3. SEM images of as-deposited and annealed $CuIn_5S_8$ thin films at: 100 °C, 150 °C, 200 °C, 250 °C and 300 °C.

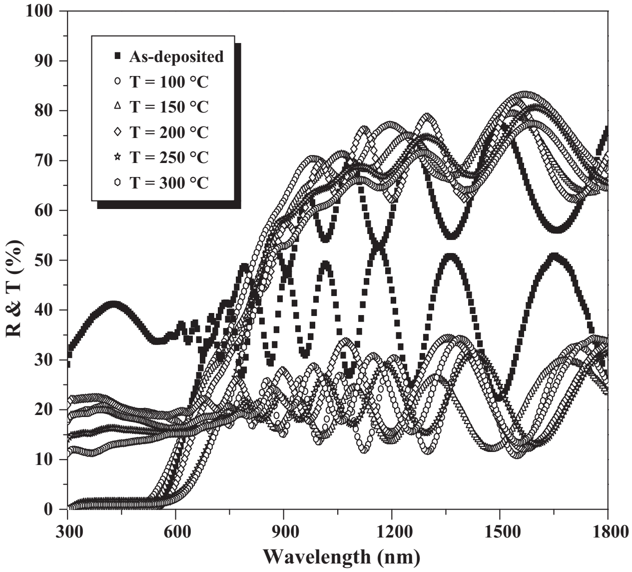

Fig. 4. Optical transmission and reflection spectra of as-deposited and annealed $CuIn_5S_8$ thin films at various temperatures.

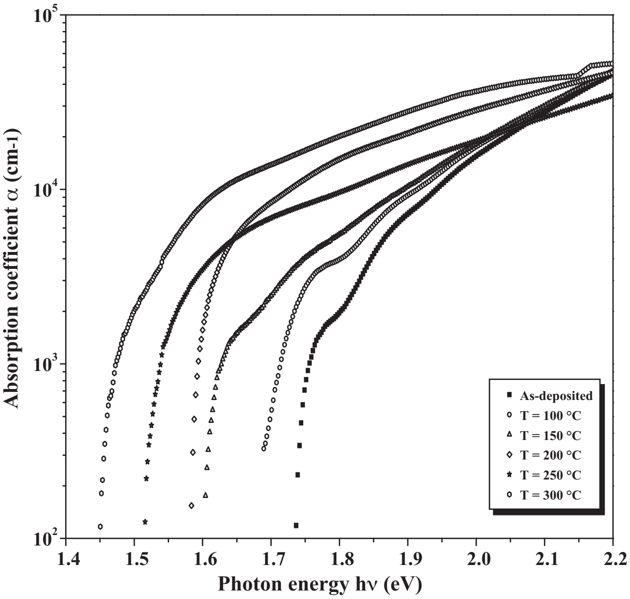

Fig. 5. Absorption spectra of as-deposited and annealed $CuIn_5S_8$ thin films at various temperatures.

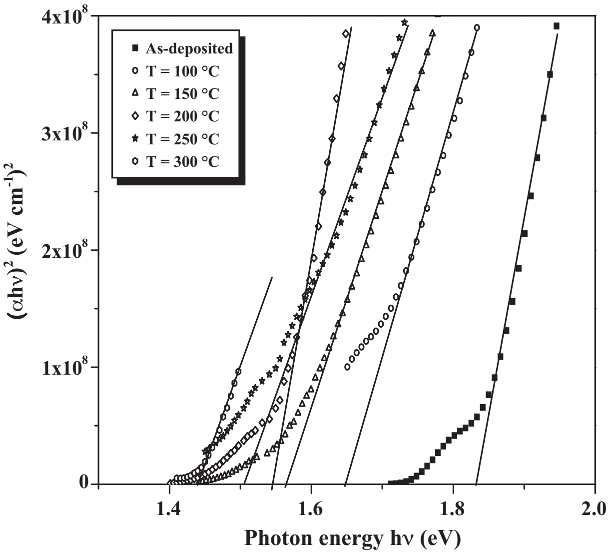

Fig. 6. Plots of $(\alpha h\nu)^2$ versus $(h\nu)$ for the $CuIn_5S_8$ thin films at various annealing temperatures.